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High resolution X-ray diffraction and photoluminescence of $\text{InAs}_{1-x}\text{Sb}_x/\text{GaSb}$

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Abstract content (Max 300 words) **Formatting** **Special chars**

$\text{InAs}_{1-x}\text{Sb}_x$ has the lowest energy band gap among all the III-V semiconductors and has thus received a great deal of attention as an important material to be incorporated into infrared optoelectronic devices. Photodetectors containing this ternary have potential to reach wavelengths up to 9 μm . To achieve this, high quality thin films with few defects and impurities are required. One of the key issues in using $\text{InAs}_{1-x}\text{Sb}_x$ in the device architecture (particularly for wavelengths greater than 4 μm) is the lack of available lattice-matched substrates. To date, the best performing InAsSb -containing devices are lattice matched to GaSb substrates, with a 9% antimony solid content. (i.e. $\text{InAs}_{0.91}\text{Sb}_{0.09}$).

This paper focuses on the deposition of high quality thin films of $\text{InAs}_{0.91}\text{Sb}_{0.09}$ (between 2 μm and 4 μm thick) on 2" GaSb substrate. The material deposition is performed in a metal organic chemical vapour deposition (MOCVD) system. The process begins by the deposition of a thin (nanometer thickness range) low temperature buffer layer of either GaSb followed by the deposition of strain free InAsSb . High resolution X-ray diffraction (HRXRD) is used to precisely determine the composition of the ternary alloy as well as to investigate the uniformity across the entire wafer. Photoluminescence (PL), using a Fourier-transform infrared (FTIR) spectrometer, is employed to further explore the material quality and purity. Preliminary measurements indicate consistent thickness and compositional uniformity of the InAsSb layers.

Apply to be considered for a student award (Yes / No)?

No

Level for award (Hons, MSc, PhD, N/A)?

PhD

Main supervisor (name and email) and his / her institution

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